FISCHERSCOPE® X-RAY XDAL®

One device, many possibilities: Coating thickness measurement, material analysis and trace analysis

Fully automatable: Let your instrument work for

you with just one click

Compact design: Very

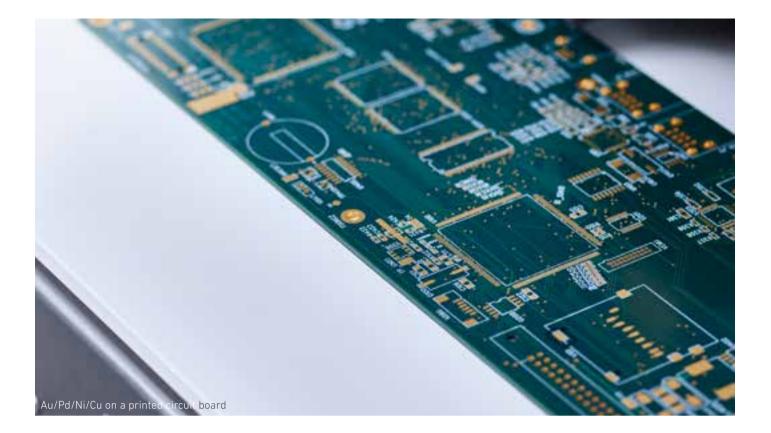
good compromise between performance and space requirements



Testing of multiple measuring points: Even with

large samples, measuring points are possible on the entire sample surface

Also for large samples: Hood with C-slot **Commissioning:** Extremely fast and simple



The best detectors for thin layers

With its semiconductor detectors and the programmable measuring table, the FISCHERSCOPE® X-RAY XDAL® series is an excellent choice for fast and accurate measurements of solder composition. This makes it possible to eliminate the risk of getting different solder batches via a simple scan at incoming goods inspection.

The XDAL® series is also well suited for applications that require testing thin and ultra-thin coatings $< 0.05 \,\mu$ m. This allows, for example, expensive materials to be saved and process-reliable production to be carried out. Mass inspection of different components in production control and incoming goods can also be completed.

The instrument version with a 50 mm² silicon drift detector is suitable for RoHS measurements.



HSS drill bit: TiN/Fe



High reliability: Pb (> 3 %) in electronic components

Features

- Universal instrument for automated measurements of thin and very thin layers < 0.05 µm and for material analysis in the ppm range
- Stepless measuring distance with measuring top down
- Microfocus tube with tungsten anode
- 4-fold changeable apertures
- 3-fold changeable filter
- Various semiconductor detectors ensure very good detection accuracy and high resolution: silicon PIN and silicon drift detector
- Optionally also available with fixed or manual measuring table
- Fully protected instrument with type approval according to current radiation protection legislation